

NOVA MEASURING INSTRUMENTS LTD  
Form 6-K  
July 07, 2005

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**FORM 6-K**  
**SECURITIES AND EXCHANGE COMMISSION**

Washington, D.C. 20549  
Report of Foreign Private Issuer  
Pursuant to Rule 13a-16 or 15d-16  
of the **Securities Exchange Act of**  
**1934**

July 7<sup>th</sup>, 2005

**NOVA MEASURING INSTRUMENTS LTD.**

Building 22 Weitzmann Science Park, Rehovoth  
P.O.B 266

[Indicate by check mark whether the registrant files or will file  
annual reports under cover Form 20-F or Form 40-F.

Form 20-F  Form 40-F

[Indicate by check mark whether the registrant by furnishing the  
information contained in this Form is also thereby furnishing the  
information to the Commission pursuant to Rule 12g3-2(b) under the  
Securities Exchange Act of 1934.

Yes  No

If  Yes is marked, indicate below the file number assigned to the  
registrant in connection with Rule 12g3-2(b): N/A.

Attached hereto and incorporated by way of reference herein the Registrants notice regarding: the Enhanced Throughput Integrated NovaScan  
3090CD with Multiple Etch System Manufacturers

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Signatures

Pursuant to the requirements of the Securities Exchange Act of 1934, the registrant has duly caused this report to be signed on its behalf by the  
undersigned, thereunto duly authorized.

July 7<sup>th</sup>, 2005

Nova Measuring Instruments Ltd  
Nova Measuring Instruments Ltd (the "Registrant")

BY: /S/ Chai Toren

Chai Toren

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**Nova Introduces the Enhanced Throughput Integrated NovaScan 3090CD  
with Multiple Etch System Manufacturers**

**Nova continues the introduction of its NovaScan 3090 Series for additional  
semiconductor manufacturing processes and OEM integrations**

Rehovot, Israel July 7, 2005 Nova Measuring Instruments Ltd. (NASDAQ: NVMI), the market leader in integrated measurement and process control for the semiconductor industry, today announced the successful integration of its enhanced NovaScan 3090CD metrology system on several etchers. In March 2005, Nova previously announced the successful integration of the system on a Lam Research Corporation 2300 Exelan<sup>®</sup> Etch System.

The **NovaScan 3090CD** series forms an advanced metrology platform for Critical Dimension (CD) control and profile measurements, and is designed so that it can operate both as an integrated metrology and standalone platform for 200mm and 300mm systems, for 65nm IC manufacturing and beyond. It is based on Nova's earlier field proven technology platform, the NovaScan 3060CD system. NovaScan 3090CD is integrated using the exact same configuration as the NovaScan 3060CD system, thus offering customers an easy upgrade path. Equipped with a single polarized channel, from Deep-UV to Near-IR, the NovaScan 3090CD supports the measurement of 2D structures and enables 3D shape characterization.

The NovaScan 3090CD system provides real-time measurement of CD, trench depth, photoresist height, thickness and shape of complex layer stacks. The reliable single channel system provides the highest throughput of an integrated system in the market, while maintaining the cleanliness and hermetic structure needed to operate in different process conditions. The system demonstrates a 100% performance improvement in metrology capabilities over the NovaScan 3060CD, with enhanced throughput capabilities, while integration and physical layout remain unchanged.

Dr. Giora Dishon, Nova's President & CEO, states: Our newest process control solutions include metrology capabilities for oxide CMP along with new enabling methods and systems for copper CMP, CVD, Photolithography and Etch. Scatterometry based systems and SW are becoming the dominant leading edge technology enabling advanced process control, and the integration of the NovaScan 3090CD system in multiple etchers offers IC manufacturers advanced integrated metrology solutions for all etch processes. We will continue to bring new systems, solutions and capabilities to meet the needs of high volume manufacturing with advanced technologies of 65nm and beyond.

**About Nova:** Nova Measuring Instruments Ltd. develops, designs and produces integrated process control systems in the semiconductor manufacturing industry. Nova provides a broad range of integrated process control solutions that link different semiconductor processes and process equipment. The Company's website is [www.nova.co.il](http://www.nova.co.il)

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